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U.S. UTILITY Patent Application
 O.I.P.E. PATENT DAYE
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SCANNED BK Q.A. 4 EXAMINER SUBCLASS ART UNIT CLASS CONT/PRIOR APPLICATION NO. 2133 726 714 09/679042 RSD Wajih Dalal Masashi Shimanouchi Robert Glenn Burnell West Méthod and apparatus for high speed IC test Interface TITLE

ISSUING CLASSIFICATION										
ORIGIN	AL		CROSS REFERENCE(S) SUBCLASS (ONE SUBCLASS PER BLOCK)							
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DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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(Assistant Examiner) (Date)				
			ISS	UE FEE
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(Primary Examiner) (Date)				
			ISSUÆ BA	TCH NUMBER
(Legal Instruments Examiner) (Date)		(Date)		
	(Assistant	Sheets Drwg. Figs. Drwg. (Assistant Examiner)	Sheets Drwg. Figs. Drwg. Print Fig. (Assistant Examiner) (Date)	Sheets Drwg. Figs. Drwg. Print Fig. Total Claims NOTICE OF ALL

(Rev. 6/99)